

N-Channel Enhancement Mode Field Effect Transistor

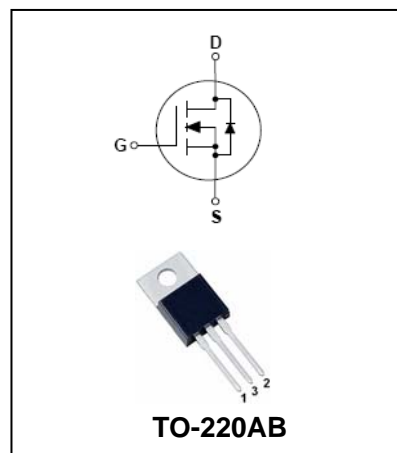
BL8N60

FEATURES

- $R_{DS(ON)} = 1.2\Omega @ V_{GS} = 10V$
- Ultra Low gate charge (typical 28nC)
- Low reverse transfer capacitance ($C_{RSS} =$ typical 12.0 pF)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability, high ruggedness



Lead-free



Ordering Information

| Part Number | Package | Shipping | Marking Code |
|-------------|----------|--------------|--------------|
| BL8N60□ | TO-220AB | 50pcs / Tube | 8N60 |

Note for □: none is for Lead-free package

“G” is for Halogen-free package

MAXIMUM RATING operating temperature range applies unless otherwise specified

| Symbol | Parameter | Value | Units |
|-----------------|--|-------------|---------------|
| V_{DS} | Drain-Source voltage | 600 | V |
| V_{GS} | Gate -Source voltage | ± 30 | V |
| I_D | Continuous Drain current $T_C=25^\circ C$ | 7.5 | A |
| | Continuous Drain current $T_C=100^\circ C$ | 4.6 | A |
| E_{AS} | Single Pulse Avalanche Energy(Note2) | 230 | mJ |
| E_{AR} | Avalanche Energy, Repetitive(Note1) | 14.7 | mJ |
| I_{AR} | Avalanche Current(Note2) | 7.5 | A |
| ISD | Continuous Drain-Source Current | 7.5 | A |
| ISM | Pulsed Drain-Source Current | 30 | A |
| dv/dt | Peak Diode Recovery dv/dt(Note4) | 4.5 | V/ns |
| P_D | Power Dissipation | 147 | W |
| | Derating Fcator above $25^\circ C$ | 0.32 | W/ $^\circ C$ |
| $R_{\theta JC}$ | Junction-to-Case | 0.85 | $^\circ C/W$ |
| $R_{\theta JA}$ | Junction-to-Ambient | 62.5 | $^\circ C/W$ |
| T_J, T_{stg} | Junction and Storage Temperature | -55 to +150 | $^\circ C$ |
| T_L | Maximum Temperature for Soldering | +150 | $^\circ C$ |

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Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

ELECTRICAL CHARACTERISTICS

| Parameter | Symbol | Test conditions | MIN | TYP | MAX | UNIT |
|---|--------------------------------------|--|-----|------|-----------|----------|
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}=0V, I_D=250\mu A$ | 600 | - | - | V |
| Bvdss Temperature Coefficient | $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | $I_D=250mA,$ | - | 0.7 | - | V/°C |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{DS}=V_{GS}, I_D=250\mu A$ | 2 | | 4 | V |
| Drain to Source Leakage Current | I_{DSS} | $V_{DS}=600V, V_{GS}=0V$ | - | - | 10 | μA |
| Static drain-Source on-resistance | $R_{DS(ON)}$ | $V_{GS}=10V, I_D=3.75A$ | - | 1.0 | 1.2 | Ω |
| Gate-body Leakage Forward Reverse | I_{GSS} | $V_{GS}=\pm 30V$ | | | ± 100 | nA |
| Input Capacitance | C_{iss} | $V_{GS}=0V, V_{DS}=25V$ $f=1.0MHz$ | - | 965 | 1255 | pF |
| Output Capacitance | C_{oss} | | - | 105 | 135 | |
| Reverse Transfer Capacitance | C_{rss} | | - | 12 | 16 | |
| Turn-on Delay Time | $t_{d(ON)}$ | $I_D=7.5A, V_{DD}=300V$ | - | 16.5 | 45 | ns |
| Rise Time | t_r | | - | 60.5 | 130 | |
| Turn-Off Delay Time | $t_{d(OFF)}$ | | - | 81 | 170 | |
| Fall Time | t_f | | - | 64.5 | 140 | |
| Total Gate Charge | Q_g | $I_D=1.2A, V_{DD}=480V$ $V_{GS}=10V$ | - | 28 | 36 | nC |
| Gate to Source Charge | Q_{gs} | | - | 4.5 | | nC |
| Gate to Drain ("Miller") Charge | Q_{gd} | | - | 12 | | nC |
| Reverse Recovery Time | t_{rr} | $I_S=7.5A, T_J=25^\circ C$ $dI_F/dt=100A/\mu s,$ $V_{GS}=0V$ | - | 365 | - | ns |
| Reverse Recovery Charge | Q_{rr} | | - | 3.4 | - | nC |

Note: 1. Repetitive Rating : Pulse width limited by T_J

2. $L=7.3mH, I_{AS}=7.5A, V_{DD}=50V, R_G=25\Omega, \text{Starting } T_J=25^\circ C$

3. $I_{SD}\leq 7.5A, di/dt\leq 200A/\mu s, V_{DD}\leq BV_{DSS}, \text{Starting } T_J=25^\circ C$

4. Pulse Test: Pulse width $\leq 300\mu s, \text{Duty cycle}\leq 2\%$

5. Essentially independent of operating temperature

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PACKAGE OUTLINE

Plastic surface mounted package

TO-220AB

